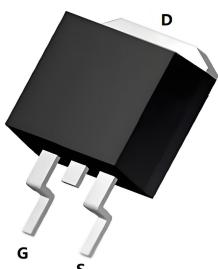


## N-Channel 60V(D-S) MOSFET

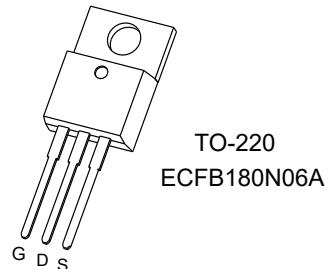
Product summary		
$V_{DS}$	60	V
$R_{DS(ON)}$ (at $V_{GS}=10V$ ) Typ.	2.7	$m\Omega$
$I_D(T_c=25^\circ C)$	180	A

Features
<ul style="list-style-type: none"> <li>High density cell design for low <math>R_{DS(ON)}</math></li> <li>Trench Power MV MOSFET technology</li> </ul>
Applications
<ul style="list-style-type: none"> <li>Load Switch</li> <li>PWM Application</li> <li>Power management</li> </ul>

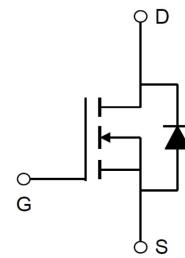
### Pin Configuration



TO-263  
ECFC180N06A



TO-220  
ECFB180N06A



### Packing Information

Device	Package	Reel Size	Quantity(Min. Package)
ECFC180N06A	TO-263	13"	800pcs

### Absolute Maximum Ratings (at $T_A=25^\circ C$ Unless Otherwise Noted)

Symbol	Parameter	Rating	Units
$V_{DS}$	Drain-Source Voltage	60	V
$V_{GS}$	Gate-Source Voltage	$\pm 20$	V
$I_D$	Continuous Drain Current	$T_c=25^\circ C$	A
		$T_c=100^\circ C$	A
$I_{DM}$	Pulse Drain Current Tested <sup>A</sup>	720	A
$E_{AS}$	Single Pulse Avalanche Energy <sup>B</sup>	324	mJ
$P_D$	Power Dissipation $T_c=25^\circ C$	258	W
$T_J, T_{STG}$	Junction and Storage Temperature Range	-55 to +175	$^\circ C$

### Thermal Characteristics

Symbol	Parameter	Typical	Units
$R_{eJC}$	Thermal Resistance-Junction to case	0.58	$^\circ C/W$

### Electrical Characteristics (at $T_J = 25^\circ\text{C}$ Unless Otherwise Noted)

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
<b>Static Parameters</b>						
$\text{BV}_{\text{DSS}}$	Drain-Source Breakdown Voltage	$V_{\text{GS}}=0\text{V}, I_{\text{D}}=250\mu\text{A}$	60	--	--	V
$I_{\text{DSS}}$	Zero Gate Voltage Drain Current	$V_{\text{DS}}=60\text{V}, V_{\text{GS}}=0\text{V}$	--	--	1	$\mu\text{A}$
$I_{\text{GSS}}$	Gate-Body Leakage Current	$V_{\text{DS}}=0\text{V}, V_{\text{GS}}=\pm 20\text{V}$	--	--	$\pm 100$	$\text{nA}$
$V_{\text{GS}(\text{th})}$	Gate Threshold Voltage	$V_{\text{DS}}=V_{\text{GS}}, I_{\text{D}}=250\mu\text{A}$	2.0	3.0	4.0	V
$R_{\text{DS}(\text{ON})}$	Drain-Source On-State Resistance <sup>C</sup>	$V_{\text{GS}}=10\text{V}, I_{\text{D}}=30\text{A}$	--	2.7	3.5	$\text{m}\Omega$
$V_{\text{SD}}$	Diode Forward Voltage	$I_{\text{S}}=30\text{A}, V_{\text{GS}}=0\text{V}$	--	--	1.2	V
$I_{\text{S}}$	Maximum Body-Diode Continuous Current		--	--	180	A
<b>Dynamic Parameters <sup>D</sup></b>						
$C_{\text{iss}}$	Input Capacitance	$V_{\text{GS}}=0\text{V}, V_{\text{DS}}=25\text{V}$ $f=1\text{MHz}$	--	7660	--	pF
$C_{\text{oss}}$	Output Capacitance		--	642	--	pF
$C_{\text{rss}}$	Reverse Transfer Capacitance		--	620	--	pF
$Q_g$	Total Gate Charge	$V_{\text{DS}}=30\text{V}, I_{\text{D}}=30\text{A}$ $V_{\text{GS}}=10\text{V}$	--	138	--	nC
$Q_{\text{gs}}$	Gate-Source Charge		--	21	--	nC
$Q_{\text{gd}}$	Gate-Drain Charge		--	33	--	nC
$t_{\text{D}(\text{on})}$	Turn-on Delay Time	$V_{\text{DD}}=30\text{V}, I_{\text{D}}=30\text{A}$ , $R_{\text{L}}=1\Omega, R_{\text{GEN}}=3\Omega$ , $V_{\text{GS}}=10\text{V}$	--	14	--	ns
$t_r$	Turn-on Rise Time		--	10	--	ns
$t_{\text{D}(\text{off})}$	Turn-off Delay Time		--	65	--	ns
$t_f$	Turn-off Fall Time		--	27	--	ns
$t_{\text{rr}}$	Reverse recovery time	$I_{\text{F}}=20\text{A}$ , $di/dt=100 \text{ A}/\mu\text{s}$	--	52	--	ns
$Q_{\text{rr}}$	Reverse recovery charge		--	75	--	nC

A. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature.

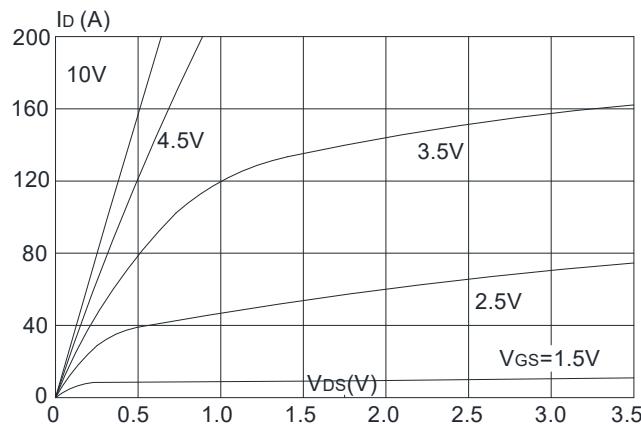
B. The EAS data shows Max. rating . The test condition is  $T_J=25^\circ\text{C}, V_{\text{DD}}=40\text{V}, V_{\text{G}}=10\text{V}, R_{\text{G}}=25\Omega, L=0.5\text{mH}, I_{\text{AS}}=36\text{A}$ .

C. The data tested by pulsed , pulse width $\leq 300\text{us}$  , duty cycle $\leq 0.5\%$ .

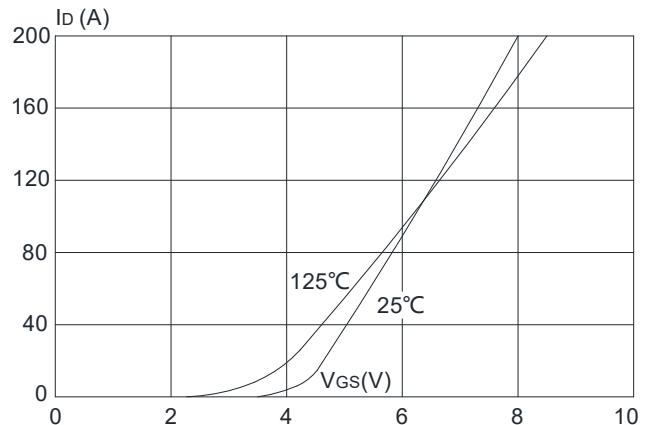
D. Guaranteed by design, not subject to production testing.

## Typical Characteristics

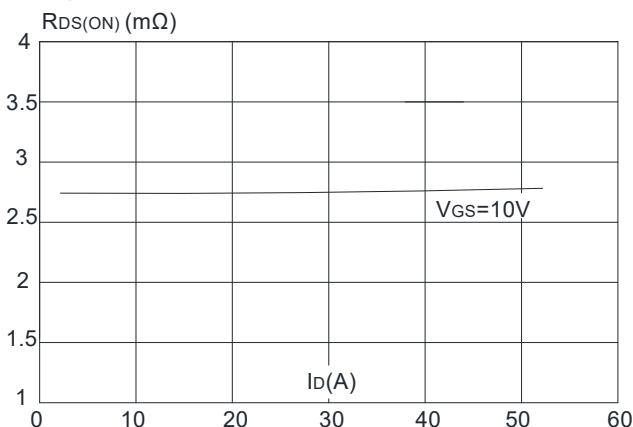
**Figure 1:** Output Characteristics



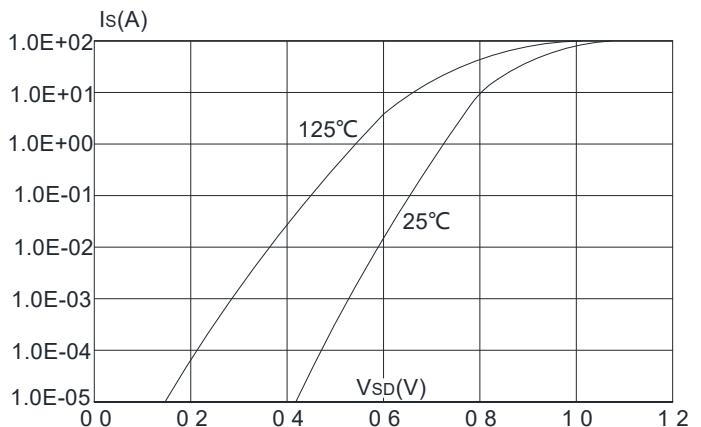
**Figure 2:** Typical Transfer Characteristics



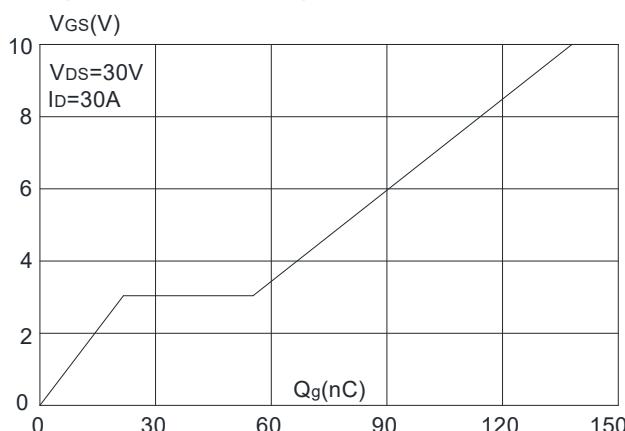
**Figure 3:** On-resistance vs. Drain Current



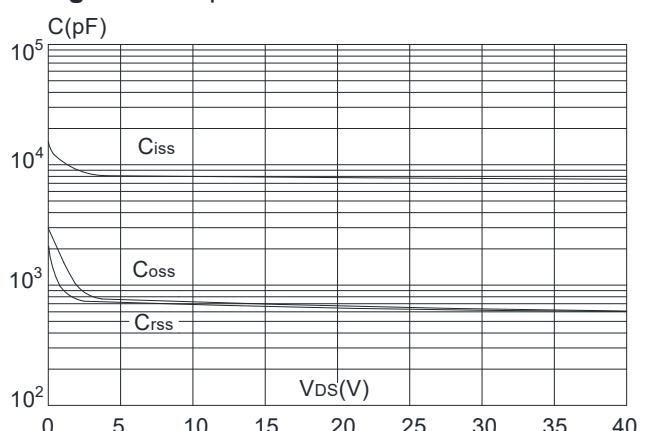
**Figure 4:** Body Diode Characteristics



**Figure 5:** Gate Charge Characteristics

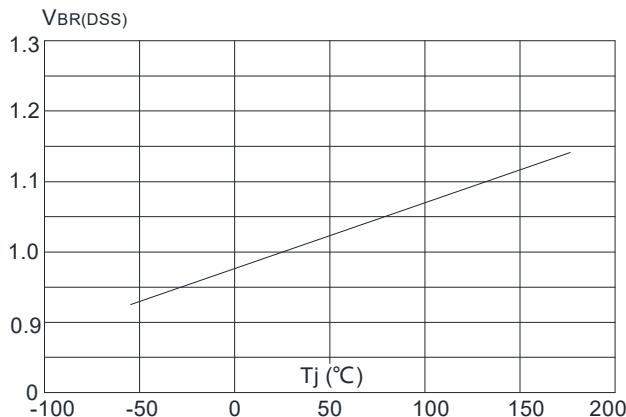


**Figure 6:** Capacitance Characteristics

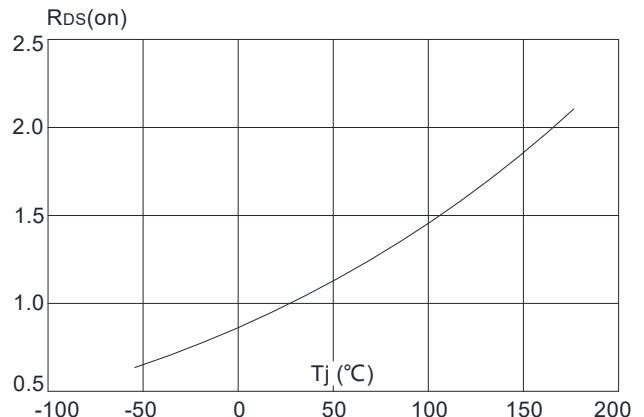


## Typical Characteristics

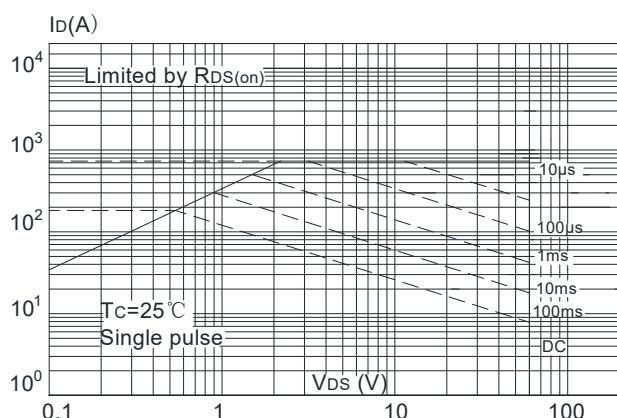
**Figure 7:** Normalized Breakdown Voltage vs. Junction Temperature



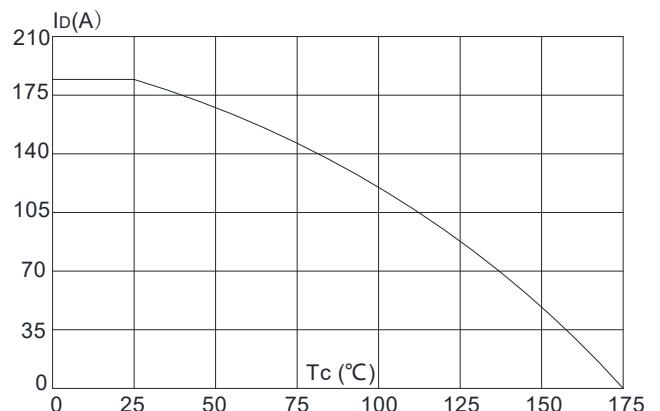
**Figure 8:** Normalized on Resistance vs. Junction Temperature



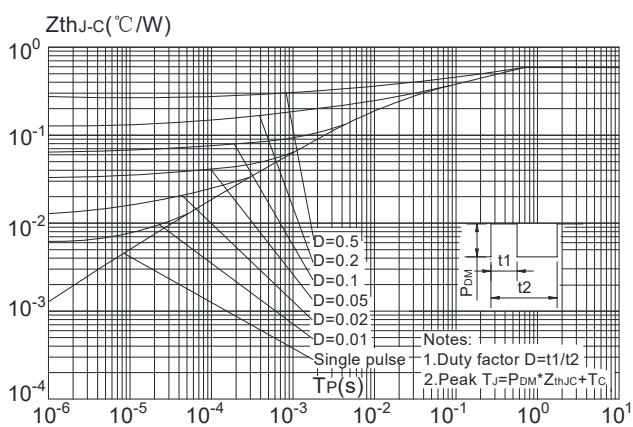
**Figure 9:** Maximum Safe Operating Area

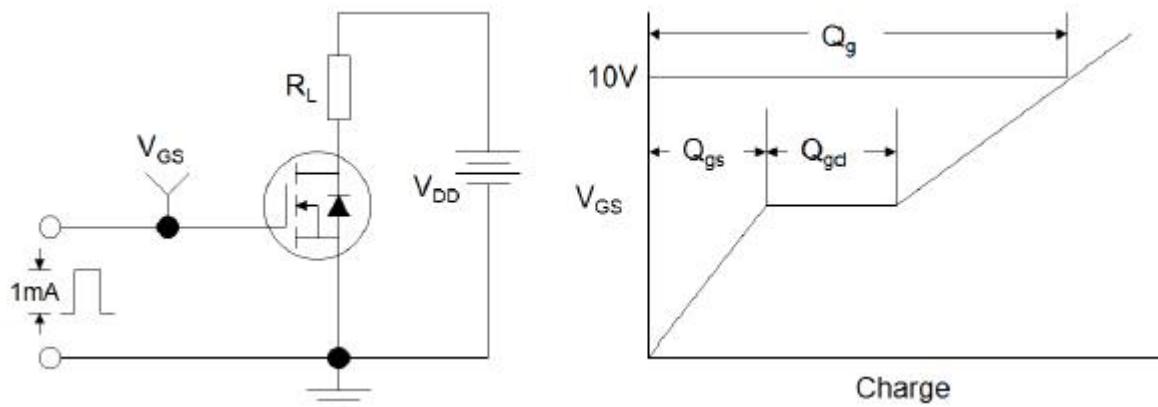
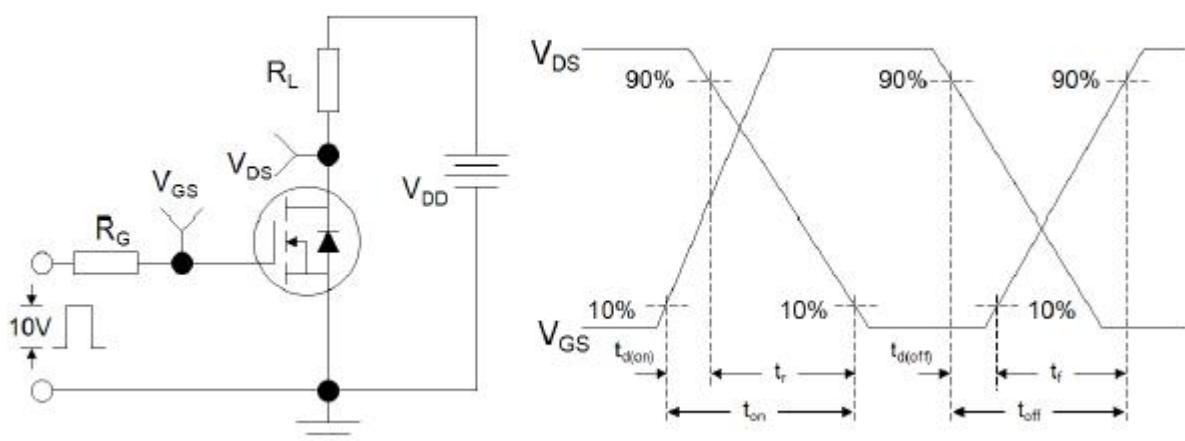
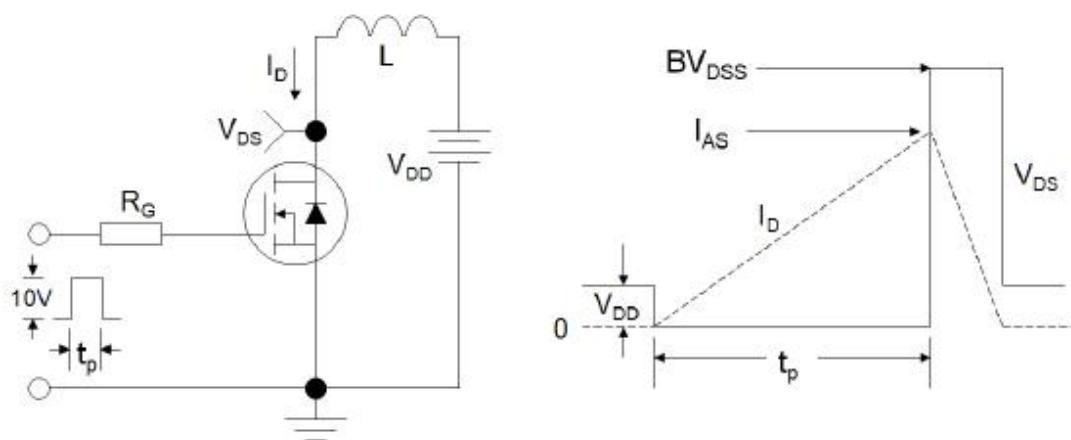


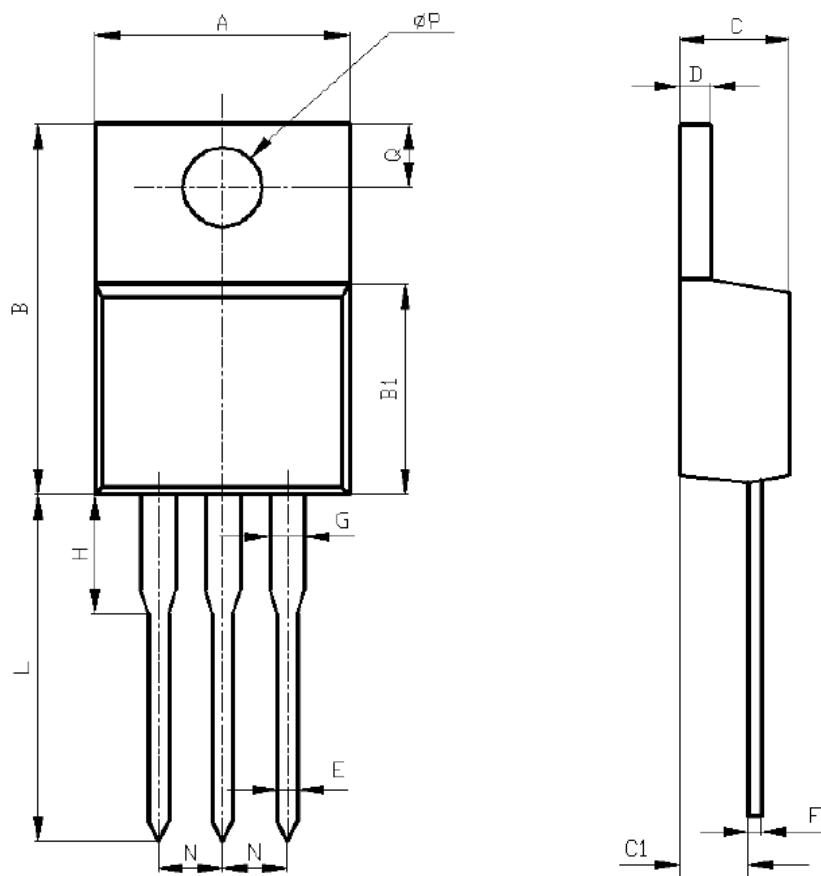
**Figure 10:** Maximum Continuous Drain Current vs. Case Temperature



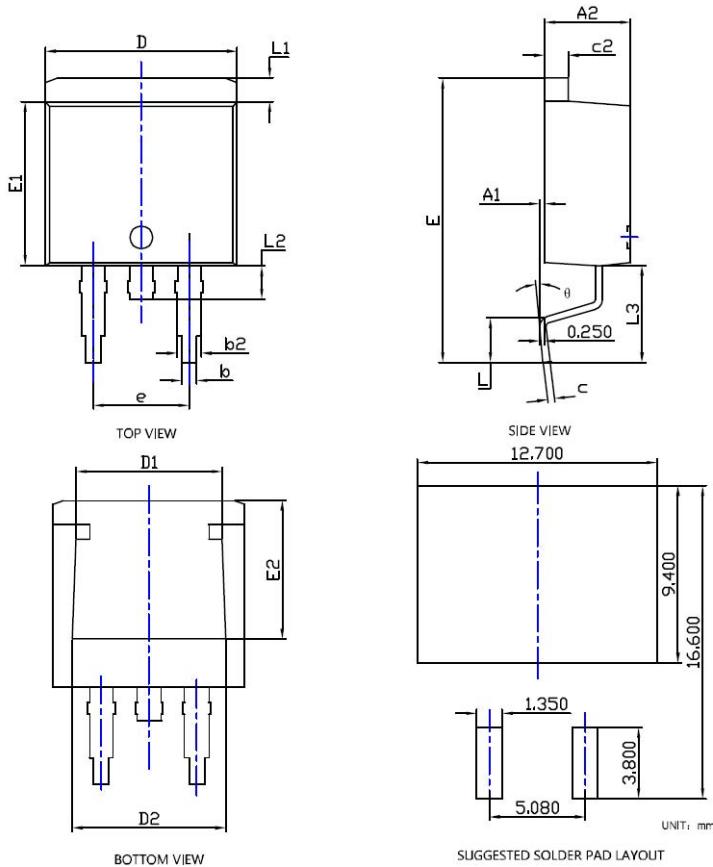
**Figure 11:** Maximum Effective Transient Thermal Impedance, Junction-to-Case



**Test Circuit**

**Figure1:Gate Charge Test Circuit & Waveform**

**Figure 2: Resistive Switching Test Circuit & Waveforms**

**Figure 3:Unclamped Inductive Switching Test Circuit & Waveforms**

**ECFB180N06A(TO-220) Package Information(mm)**


SYMBOLS	MILLIMETERS	
	MIN	MAX
A	10.10	10.50
B	15.20	15.60
B1	9.00	9.40
C	4.40	4.60
C1	2.40	3.00
D	1.20	1.40
E	0.70	0.90
F	0.40	0.60
G	1.17	1.37
H	3.30	3.80
L	13.10	13.70
N	2.34	2.74
Q	2.40	3.00
ΦP	3.70	3.90

**ECFC180N06A(TO-263) Package Information**


SYMBOL	INCHES			Millimeter		
	MIN.	NOM.	MAX.	MIN.	NOM.	MAX.
A1	0.000	---	0.010	0.000	---	0.250
A2	0.174	0.180	0.186	4.430	4,580	4.730
b	0.028	0.032	0.036	0.720	0.820	0.920
b2	0.046	0.050	0.054	1.180	1.280	1.380
c	0.013	0.015	0.018	0.330	0.390	0.450
c2	0.048	0.050	0.053	1.220	1.280	1.34
D	0.394	0.400	0.406	10.000	10.150	10.300
D1	0.295	0.307	0.319	7.500	7,800	8.100
D2	0.303	0.315	0.327	7.700	8.000	8.300
E	0.571	0.591	0.610	14,500	15,000	15,500
E1	0.337	0.341	0.348	8,550	8,700	8,850
E2	0.276	0.287	0.299	7,000	7,300	7,600
e	0.200BSC			5.080BSC		
L	0.070	---	0.110	1.790	---	2,790
L1	0.044	---	0.056	1.120	---	1,420
L2	0.030	---	0.070	0.770	---	1,770
L3	0.197REF			5.000REF		
theta	0°	---	8°	0°	---	8°

**NOTE:**

- 1.PACKAGE BODY SIZES EXCLUDE MOLD FLASH AND GATE BURRS.
- 2.TOLERANCE 0.1mm UNLESS OTHERWISE SPECIFIED.
- 3.THE PAD LAYOUT IS FOR REFERENCE PURPOSES ONLY.